

# CPW2-0600S006-Silicon Carbide Schottky Diode Chip

ZERO RECOVERY® RECTIFIER

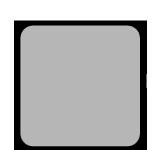
 $V_{RRM} = 600 \text{ V}$ 

 $\mathbf{I}_{\mathsf{F}(\mathsf{AVG})} = 6 \, \mathsf{A}$ 

 $\mathbf{Q}_{c} = 17 \text{ nC}$ 

## **Features**

- 600-Volt Schottky Rectifier
- Zero Reverse Recovery
- Zero Forward Recovery
- High-Frequency Operation
- Temperature-Independent Switching Behavior
- Extremely Fast Switching
- Positive Temperature Coefficient on V<sub>E</sub>



**Chip Outline** 

Part Number	Anode	Cathode	Package	Marking
CPW2-0600S006B	Al	NiV/Ag	Sawn on Foil	Wafer # on Foil

# **Maximum Ratings**

Symbol	Parameter	Value	Unit	Test Conditions	Note
V <sub>RRM</sub>	Repetitive Peak Reverse Voltage	600	٧		
V <sub>RSM</sub>	Surge Peak Reverse Voltage	600	V		
V <sub>DC</sub>	DC Blocking Voltage	600	V		
$I_{\text{F(AVG)}}$	Average Forward Current	6	А	T <sub>3</sub> =150°C	
I <sub>FRM</sub>	Repetitive Peak Forward Surge Current	30	А	$T_c=25$ °C, $t_p=10$ ms, Half Sine Wave	1
I <sub>FSM</sub>	Non-Repetitive Peak Forward Surge Current	200	А	$T_c=25$ °C, $t_p=10$ µs, Pulse	1
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature	-55 to +175	°C		



# **Electrical Characteristics**

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
V <sub>F</sub>	Forward Voltage	1.6 2.0	1.8 2.4	V	$I_F = 6 \text{ A } T_J = 25^{\circ}\text{C}$ $I_F = 6 \text{ A } T_J = 175^{\circ}\text{C}$	
$I_R$	Reverse Current	50 100	200 1000	μΑ	$V_R = 600 \text{ V } T_J = 25^{\circ}\text{C}$ $V_R = 600 \text{ V } T_J = 175^{\circ}\text{C}$	
Q <sub>c</sub>	Total Capacitive Charge	17		nC	$V_R = 600 \text{ V, } I_F = 1 \text{ A}$ $di/dt = 500 \text{ A/}\mu\text{s}$ $T_J = 25^{\circ}\text{C}$	
С	Total Capacitance	340 40 30		pF	$V_R = 0 \text{ V}, T_J = 25^{\circ}\text{C}, f = 1 \text{ MHz}$ $V_R = 200 \text{ V}, T_J = 25^{\circ}\text{C}, f = 1 \text{ MHz}$ $V_R = 400 \text{ V}, T_J = 25^{\circ}\text{C}, f = 1 \text{ MHz}$	

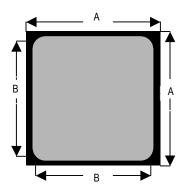
Note: 1. Assumes  $\theta JC$  Thermal Resistance of 1.8°C/W or less

## **Mechanical Parameters**

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Parameter	Тур.	Unit			
Die Size	1.55 x 1.55	mm			
Anode Pad Size	1.29 x 1.29	mm			
Anode Pad Opening	1.08 x 1.08	mm			
Thickness	377 ± 10%	μm			
Wafer Size	100	mm			
Anode Metalization (AI)	4	μm			
Cathode Metalization (NiV/Ag)	1.8	μm			
Frontside Passivation	Polyimide				



# **Chip Dimensions**



Γ	symbol	dimension			
L		mm	inch		
	Α	1.55	0.061		
	В	1.29	0.051		

Part Number	Anode	Cathode	Package	Marking
CPW2-0600S006B	Al	NiV/Ag	Sawn on Foil	Wafer # on Foil

The die-on-tape method of delivering these SiC die may be considered a means of temporary storage only. Due to an increase in adhesion over time, die stored for an extended period may affix too strongly to the tape. These die should be stored in a temperature-controlled nitrogen dry box soon after receipt. Cree will further recommend that all die be removed from tape to a waffle pack, to a similar storage medium, or used in production within 2 – 3 weeks of delivery to assure 100% release of all die without issues.